

Whose fault is it? Advanced techniques for optimizing ISO 26262 fault analysis

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Motivation

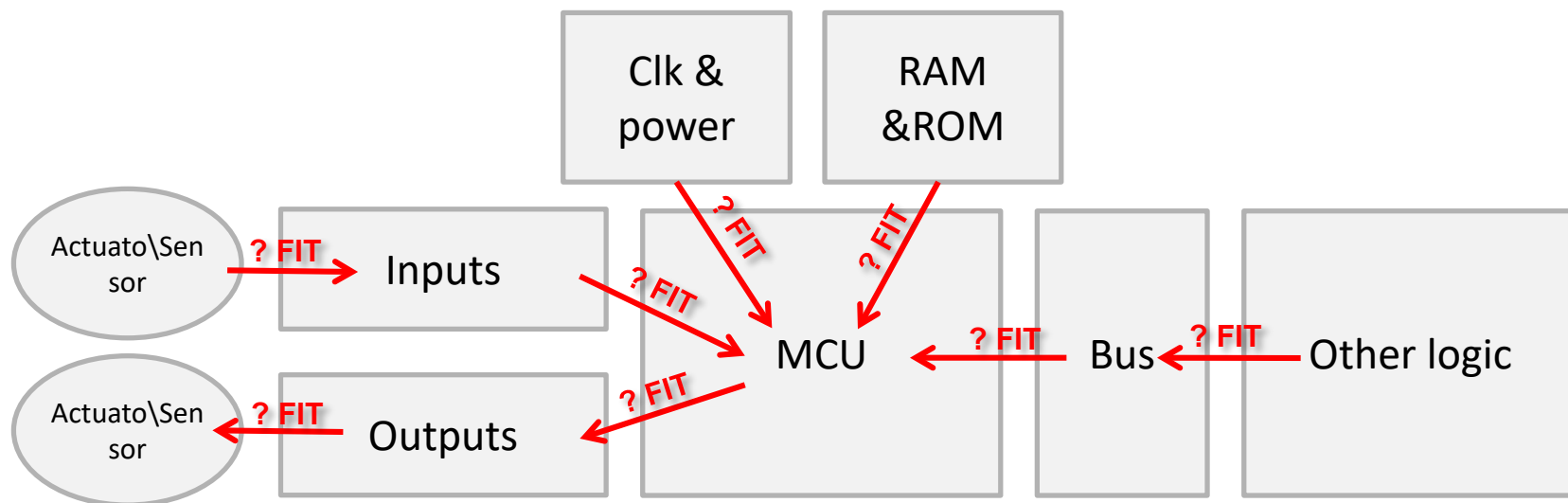
- ISO 26262 requirements for fault analysis
 - Similar requirements from other standards
- Requirements from mission-critical domains
 - Data center
 - Networking
 - And many more
- No end-to-end how to available

Agenda

- The problem
- Solution requirements
- Proposed solution

The problem : concept

- Safety concept is developed at high level
 - Failure In Time (FIT) budgets per part
 - Technical assumptions on IP (SEooC)
 - Safety mechanisms

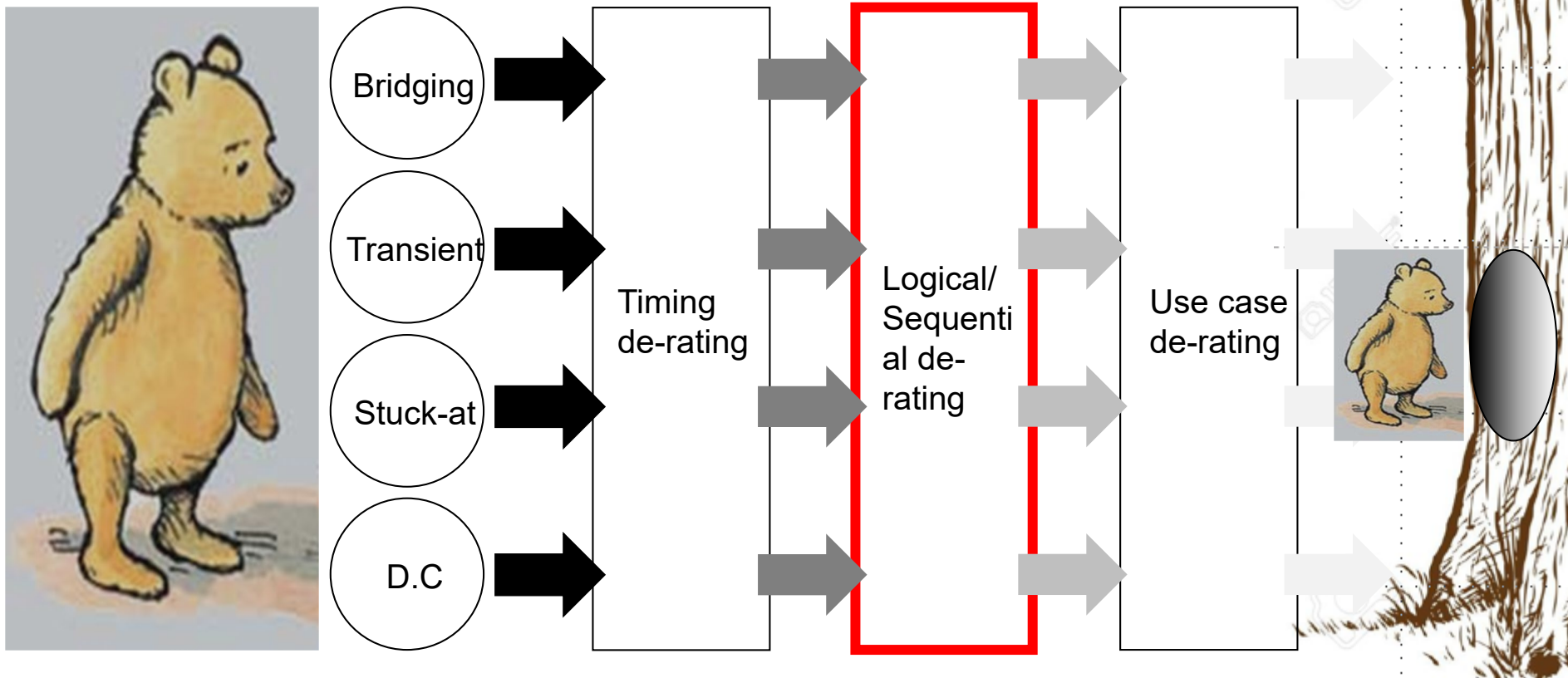


The problem : element requirements

- IP requirements derived from system analysis:
 - Contribution of element to overall FIT<10%
 - <10% of faults are single point/residual
 - Debug logic not used in safety-critical operation
 - Faults in debug logic are safe
 - More...

The problem: typical flow

- Once implementation is in place its FIT must be accurately measured



The problem: FIT doesn't fit

- What if FIT doesn't fit?
- Iterations are expensive
 - Re-plan, re-design, re-verify
 - Schedule delays



Solution requirements

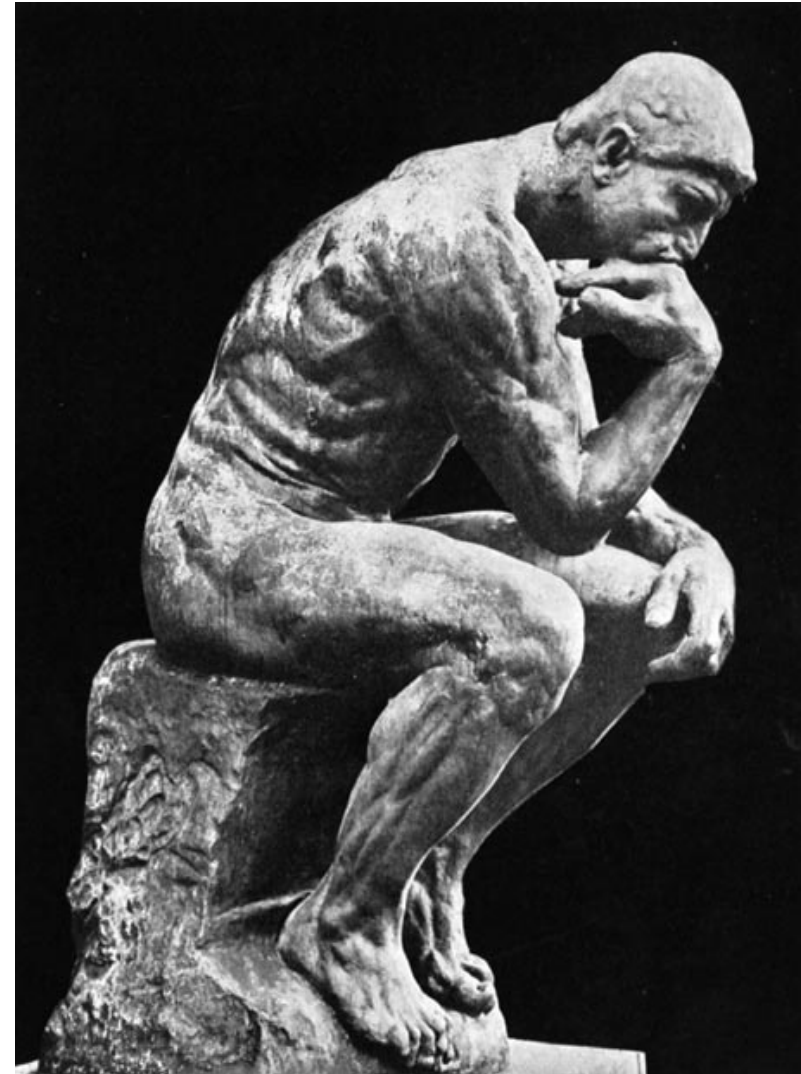
- Accuracy/cost trade-off
- Statistical strength
- Integrated with overall verification
- Seamless abstraction switch
- Multi-platform

Proposed solution

- Statistical sampling of faults
 - Population
 - Sample size
 - Fault points
 - Analysis
 - Traditional method
 - Avoiding reruns
 - Avoiding diff/duplication
 - Multi platform
 - Probabilistic metric

Population

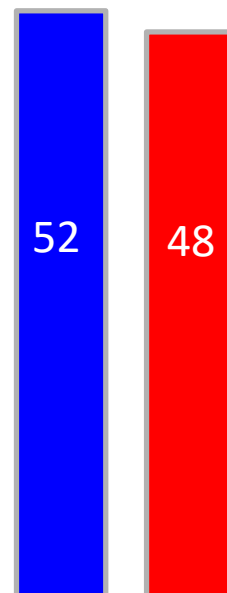
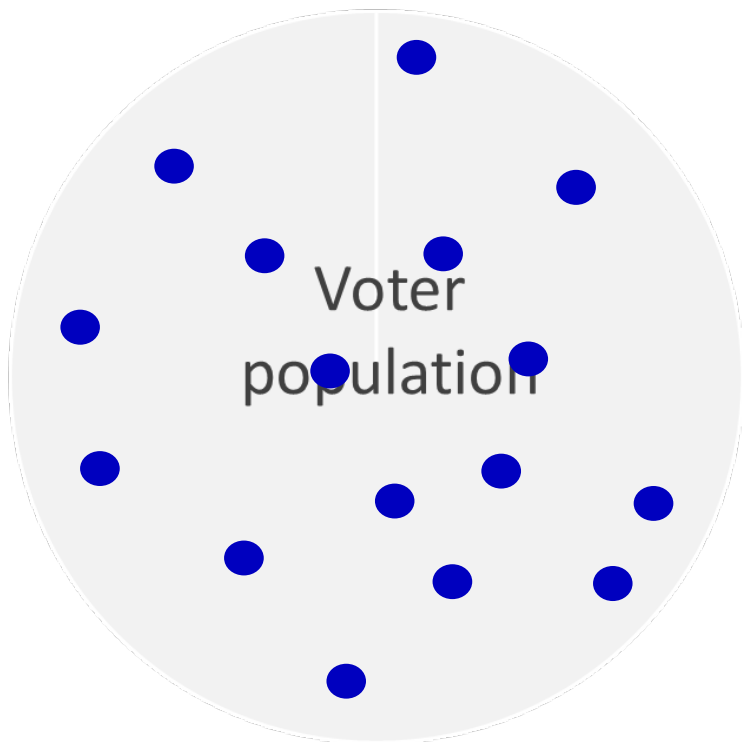
- = **test X cycle X signal?**
- Good enough:
 - Rigorous RBV
 - Interesting states covered
 - Biased to corner cases
- But:
 - Fault analysis leads to more stimuli requirements



Sample size

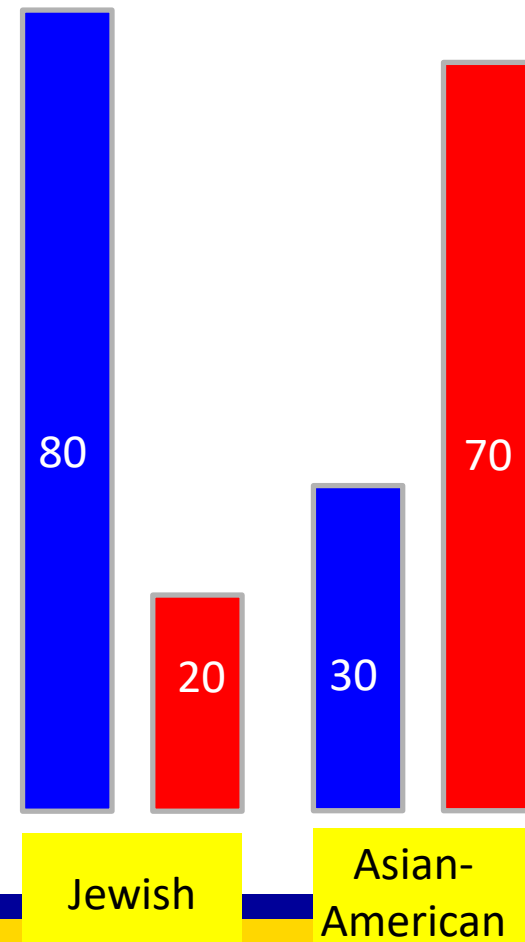
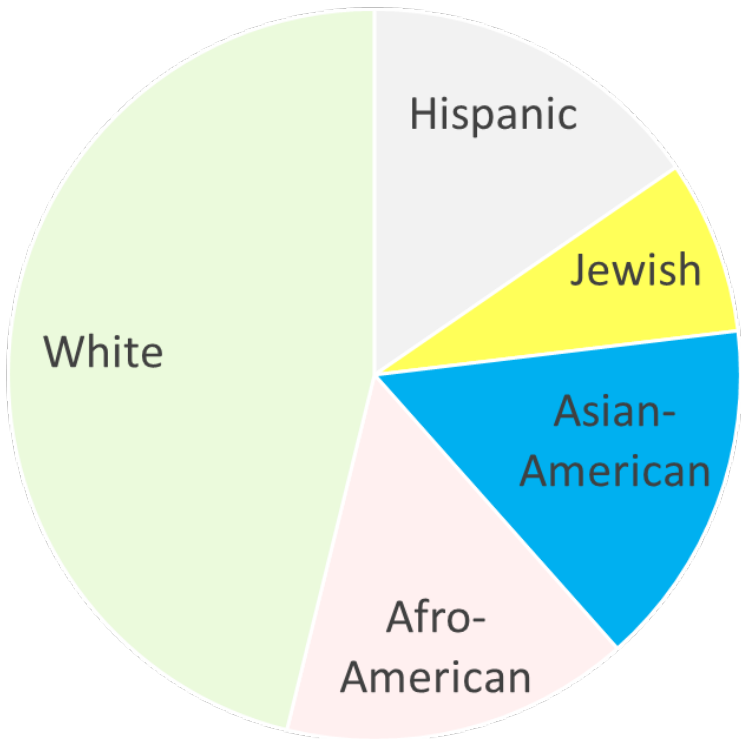
- Variance $\propto 1/\sqrt{N}$
 - Brute force method
- Sanity check:
 - $\propto$ De-rating factor
 - Let some faults -> Failures
- Final analysis:
 - $\propto$ required accuracy
- High level trade-off
 - Analysis cost $\leftrightarrow$ design cost

Fault points



Fault points

- Smaller variance -> cheaper analysis
 - Segmentation of population helps



Fault points

- Transient faults
 - SET – in logic
 - SEU – in memory
- Makes sense to separate
 - SET de-rating is lot higher
- Also, cell FIT ratio different
 - FF/Mem FIT rate higher
- Separate statistics
 - Smaller variance
 - Smaller cost

Analysis : Traditional flow

- Run reference test
- Rerun test with fault
- Diff safety critical
- How can we optimize that?

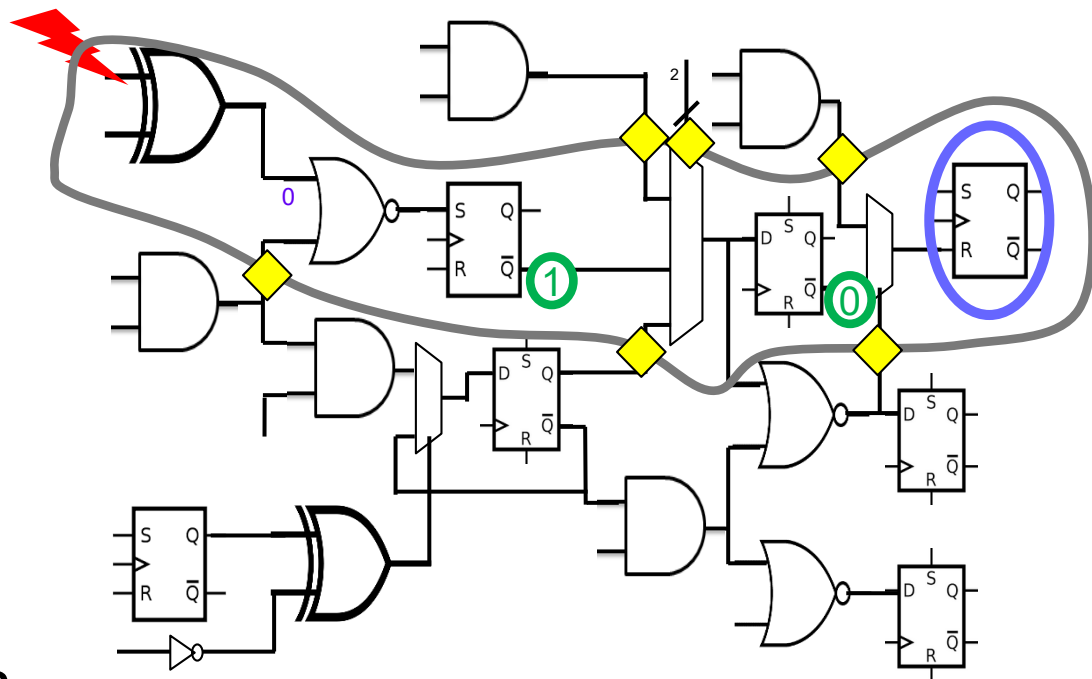
Spot the Difference Puzzle

Can you find the 15 differences?



Analysis : Minimize scope

- Time scope:
 - Fault time -> 0
- Design Scope:
 - $\cap$ between:
 - Fault point fan-out
 - Safety critical fan-in
- Stimuli
 - Initialize FFs, Mem
 - Scope inputs forced

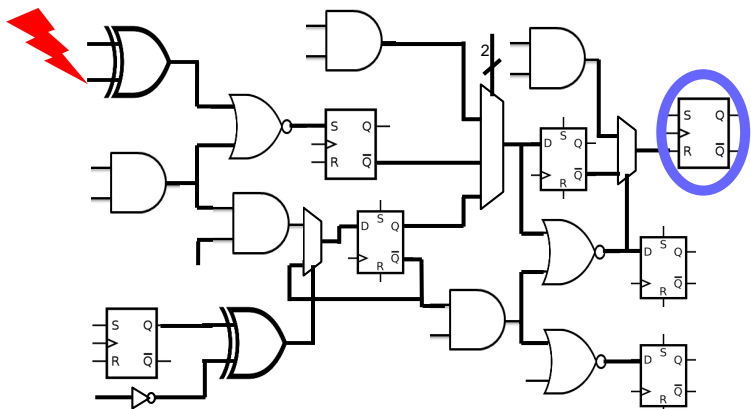


Analysis: Minimize compare

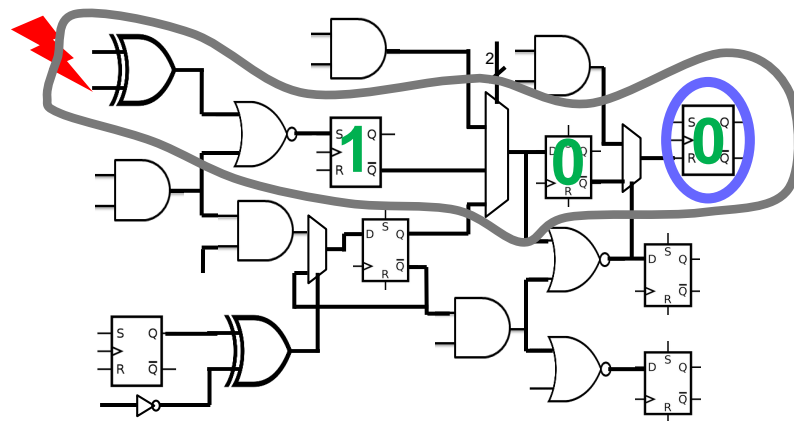
- RTL simulators already have a way to capture undefined state...
 - Good tool support
 - Attention to X optimism/pessimism (at RTL)

Analysis: decision

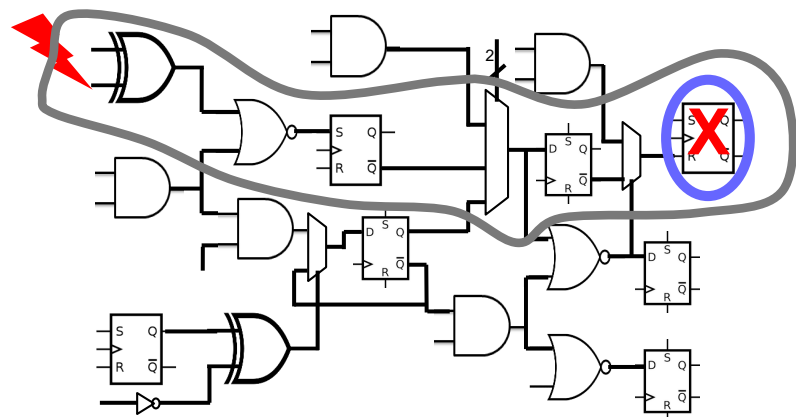
T=0



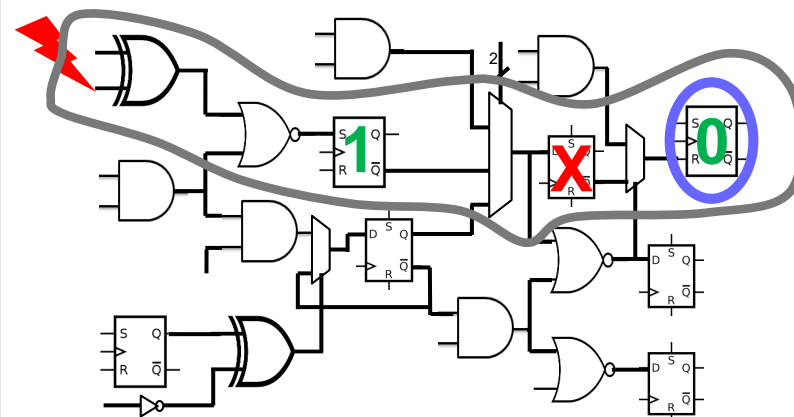
T=10 => MPF



T=10 => SPF or RF



T=End => USER



Analysis : abstraction

- RTL or structural gate?
 - SET
 - Structural gate to 1st FF
 - RTL from there
 - SEU
 - RTL all the way
- Requires RTL->GL flop mapping

Analysis: multi platform

- Emulation/prototypes can fit in flow if:
 - Results can be reproduced
 - FFs/Memories can be dumped
 - Signals into scope can be logged
- Combine platforms strengths
 - Emulation/prototyping for long runs
 - Simulation for X injection

- Example, assume no SM
- Outputs of above:
 - SEU SPF rate +/-
 - SET SPF rate +/-
- PMHF:
 - $(\text{SPF RATE}) * (\# \text{ of FF}) * (\text{FF FIT}) + \dots$
- Probability of PMHF < Target
 - Target – PMHF $\geq 5\sigma \Rightarrow 0.99999997$
 - Target – PMHF $\geq 7\sigma \Rightarrow 0.999999999999998$

Summary

- Fault simulation is an interesting challenge
 - There's more than just diff to it
 - Requires upfront consideration/planning
 - And an end-to-end flow
- Hopefully this paper will help...

Thanks